


<b>Search Notes</b>  	<b>Application/Control No.</b>  10535347	<b>Applicant(s)/Patent Under Reexamination</b>  TOY ET AL.
	<b>Examiner</b>  Neff, Michael R	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	259	2/4/2008	MRN
178	66.1	2/4/2008	MRN
327	1	2/4/2008	MRN

SEARCH NOTES		
Search Notes	Date	Examiner
Class/Subclass search performed with keyword limitations	2/4/2008	MRN
Inventor/double patenting search performed	2/4/2008	MRN
Met with SPE Shuwang Liu to discuss double patenting issues	2/4/2008	MRN
NPL search performed in IEEE xplore database	2/4/2008	MRN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner